

PG Series Gaskleen® Purifier Assemblies and Manifolds

Description

Pall's Gaskleen® PG purifier assemblies have been designed to handle process flow rates up to 1,000 slpm.

- An optional bypass manifold is available complete with isolation valves and backplate for easy mounting.
- Pall's purification materials are available in every standard configuration.
- All purifier assemblies contain an integral 316L stainless steel particle filter.
- 100% helium leak and pressure tested.
- No detectable metal contribution above background in HCl gas with HCLP material
- No detectable metal contribution above background in HBr gas with HBRP material

Specifications

Assembly Flow Rates

PG550: 75 slpmPG2400: 500 slpmPG11000: 1,000 slpm



Particle Filter Options

- PG550/PG2400: 0.4 μm or 0.003 μm
- PG11000: 0.4 µm

Connections

- ¼ in or ½ in gasket seal (VCR¹ or compatible) male/male
- Inlet/outlet isolation valves (for PG11000)

Assembly Material

- Electropolished 316L SS
- <0.25 μm/<10 μin Ra internal surface finish



Operating Conditions

- Maximum operating pressure PG550/PG2400: 3.45 MPa/500 psig PG11000: 1.72 MPa/250 psig
- Maximum operating temperature: 100°C/212°F (INP, SIP, FCP, SF6P), 40°C/104°F (GEH4P, OXP, QLXP, HCLP, HBRP, CDAP)
- EU Pressure Equipment Directive: Assemblies have been evaluated for compliance with the European Union's Pressure Equipment Directive 2014/68/EU and are CE-marked.

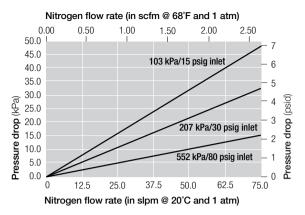
List of Purifiable Gases

Gas Family	Material	Effluent Specification ²
Nitrogen, argon, helium, xenon, krypton, neon	INP	<1 ppb H ₂ O, O ₂ , CO ₂ and CO
Silane, hydrogen, methane, cyclopropane, propane, dimethyl ether	SIP	<1 ppb H ₂ O, O ₂ , CO ₂ and CO
Carbon monoxide	SIP	<1 ppb H ₂ O, O ₂ , CO ₂ , Ni(CO) ₄ , and Fe(CO) ₅
Fluoromethane, difluoromethane, trifluorine, tetrafluoroethane, pentafluoroethane, heptafluoropropane, carbon tetrafluoride, perfluoropropane, perfluorocyclobutane, hexafluoroethane	FCP	<1 ppb H ₂ O, O ₂ , CO ₂ and CO
Germane	GEH4P	<1 ppb H ₂ O, O ₂ , CO ₂ and CO
Sulfur hexafluoride	SF6P	<1 ppb H ₂ O, O ₂ , CO ₂ and CO
Air, carbon dioxide, oxygen, nitrous oxide	OXP	<10 ppb H ₂ O
Boron trichloride, chlorine, trichlorosilane, dichlorosilane	CLXP	<100 ppb H ₂ O
Hydrogen chloride	HCLP	<15 ppb H ₂ O
Hydrogen bromide	HBRP	< 50 ppb H ₂ O
Photolithography clean dry air	CDAP	< 1 ppb H ₂ O, < 300 ppt organics (as C ₄), < 10 ppt acid gases (as SO ₂), < 15 ppt basic gases (as NH ₃), < 1 ppt refractory compounds (as HMDSO)

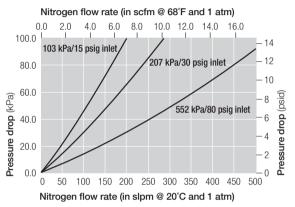
² As tested in inert gas.

¹ VCR is a trademark of Swagelok Co.

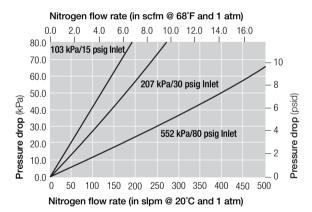
Pressure Drop vs. Gas Flow Rate



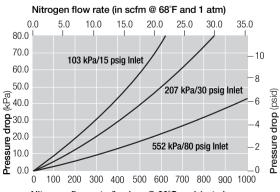
PG550 with 0.003 µm filter



PG2400 VMM4 with 0.003 µm filter

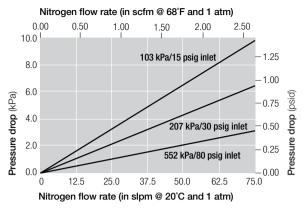


PG2400___VMM8 with 0.003 µm filter

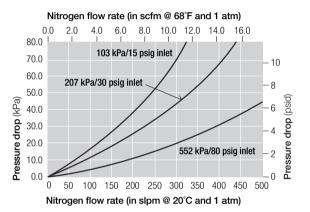


Nitrogen flow rate (in slpm @ 20°C and 1 atm)

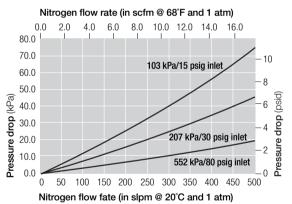
PG11000 Series assembly



PG550 with 0.4 µm filter



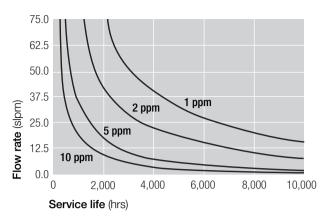
PG2400___VMM4 with 0.4 µm filter



PG2400___VMM8 with 0.4 µm filter

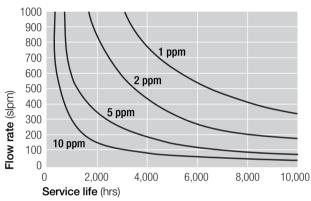
Note: For pressure drop information for a specific application, please contact Pall Microelectronics.

Lifetime Calculations



Pall AresKleen™ purification material: inert gas service Gaskleen® PG550 purifier assembly, part # GLP9INPVMM4

Inlet pressure: 207 kPa (30 psig) contaminant challenge as H₂O



Pall AresKleen™ purification material: inert gas service Gaskleen® PG11000 purifier assembly, part # GLP110INPVFM8

Inlet pressure: 207 kPa (30 psig) contaminant challenge as H₂O

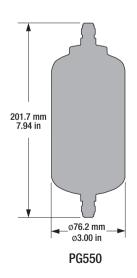
500 450 400 350 1 ppm 300 250 Flow rate (slpm) 2 ppm 200 150 5 ppm 100 50 10 ppm 0 0 6,000 2,000 4,000 8,000 10,000 Service life (hrs)

Pall AresKleen[™] purification material: inert gas service Gaskleen[®] PG2400 purifier assembly, part # GLP24INPVMM4/VMM8

Inlet pressure: 207 kPa (30 psig) contaminant challenge as H₂O

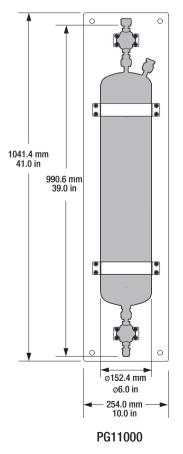
Note: For lifetime calculations in a specific application, please contact Pall Microelectronics.

Nominal Assembly Dimensions



439.4 mm 17.30 in 0101.6 mm 04.00 in PG2400

Note: For manifold dimensions, please contact Pall Corporation.



Technical Information

Impurity Removal as Tested in Specific Gases

Specific Gas	Impurity Removal Efficiency	
Inert gases: nitrogen, argon, helium, xenon, krypton, neon	$<$ 1 ppb $\rm H_2O$, $\rm CO_2$, $\rm O_2$, and $\rm CO$, as tested in argon and nitrogen using APIMS analyzer	
Flammable gases: silane, hydrogen, methane, ethane, cyclopropane, propane, dimethyl ether	<1 ppb H ₂ O, CO ₂ , O ₂ , and CO, as tested in argon, nitrogen and hydrogen using APIMS analyzer <1 ppb H ₂ O, as tested in carbon monoxide using trace moisture analyzer H ₂ O and siloxanes removed to trace levels, as	
Carbon monoxide	tested in silane using APIMS <1 ppb Ni(CO) ₄ , and < 1 ppb Fe(CO) ₅ , as tested in carbon monoxide using GC-ECD analyzer	
Fluorocarbons: fluoromethane, difluoromethane, trifluoromethane, tetrafluoroethane, pentafluoroethane, heptafluoropropane, carbon tetrafluoride, perfluoropropane, perfluorocyclobutane, hexafluoroethane	<1 ppb H ₂ O, CO ₂ , O ₂ , and CO, as tested in argon and nitrogen using APIMS analyzer <1 ppb O ₂ , as tested in trifluoromethane using trace oxygen analyzer <10 ppb H ₂ O, as tested in trifluoromethane using trace moisture analyzer and FTIR	
Germane	<1 ppb H ₂ O, CO ₂ , O ₂ , and CO, as tested in argon and nitrogen using APIMS analyzer	
Sulfur hexafluoride	<1 ppb H ₂ O, CO ₂ , and O ₂ , as tested in argon using APIMS	
Oxygenated gases: carbon dioxide, oxygen, nitrous oxide, clean dry air	<10 ppb H_2O <1 ppb H_2O , and CO_2 , as tested in argon using APIMS analyzer	
Chlorinated gases: boron trichloride, chlorine, trichlorosilane, dichlorosilane	<100 ppb H ₂ O <1 ppb H ₂ O, and CO ₂ , as tested in argon using APIMS analyzer	
Halogenated gases: hydrogen chloride, hydrogen bromide	< 15 ppb H ₂ O as tested in hydrogen chloride using CRDS < 50 ppb H ₂ O as tested in hydrogen bromide using CRDS < 1 ppb H ₂ O as tested in argon using APIMS analyzer	
Photolithography clean dry air	< 1 ppb H ₂ O as tested in argon using APIMS analyzer < 300 ppt C ₄ H ₈ as tested in argon using APIMS Analyzer < 10 ppt SO ₂ as tested in nitrogen using ion chromatograph < 15 ppt NH ₃ as tested in nitrogen using ion chromatograph < 1 ppt HMDSO as tested in argon using APIMS analyzer and baseline subtraction	

Unit conversion: 1 bar = 100 kilopascals

Part Numbers / Ordering Information

Series	Part Number ³	Description	
PG550	GLP9xxxxFVMM4	Purifier assembly, 75 slpm, 0.003 µm filter, ¼ in gasket seal (VCR or compatible) male/male	
	GLP9xxxxFMAN	Bypass manifold with GLP9xxxFVMM4 assembly	
	GLP9xxxxFVMM4GCMAN	Gas cabinet manifold with GLP9xxxFVMM4 assembly	
	GLP9xxxxVMM4	Purifier assembly, 75 slpm, 0.4 µm filter, ¼ in gasket seal (VCR or compatible) male/male	
	GLP9xxxxMAN	Bypass manifold with GLP9xxxVMM4 assembly	
	GLP9xxxxVMM4GCMAN	Gas cabinet manifold with GLP9xxxVMM4 assembly	
PG2400	GLP24xxxxFVMM4	Purifier assembly, 300 slpm, 0.003 µm filter, ¼ in gasket seal (VCR or compatible) male/male	
	GLP24xxxxFVMM8	Purifier assembly, 300 slpm, 0.003 µm filter, ½ in gasket seal (VCR or compatible) male/male	
	GLP24xxxxFMAN	Bypass manifold with GLP24xxxxFVMM8 assembly	
	GLP24xxxxVMM4	Purifier assembly, 500 slpm, 0.4 µm filter, ¼ in gasket seal (VCR or compatible) male/male	
	GLP24xxxxVMM8	Purifier assembly, 500 slpm, 0.4 µm filter, ½ in gasket seal (VCR or compatible) male/male	
	GLP24xxxxMAN	Bypass manifold with GLP24xxxxVMM8 assembly	
PG11000	GLP110xxxxVFM84	Purifier assembly, 1,000 slpm, 0.4 µm filter, ½ in gasket seal (VCR or compatible) female inlet/male outlet	
	GLP110xxxxMAN4	Bypass manifold with GLP110xxxVMM8 assembly	

³ See list of purifiable gases on page 1. Example: GLP9INPFVMM4.

⁴ The PG11000 stainless steel assembly (used with all GLP110 part numbers) is fabricated in accordance with the ASME BPVC Section VIII, Division 1, and has a U-stamp. If the user determines that an L-stamp is required for a lethal service application, please contact Pall Microelectronics for cost and availability.